

Docket No.: P2001,0337

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : ROLF HEINE ET AL.
Filed : CONCURRENTLY HERewith
Title : METHOD FOR PERFORMING AN ALIGNMENT MEASUREMENT OF
TWO PATTERNS IN DIFFERENT LAYERS ON A SEMICONDUCTOR
WAFER

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:

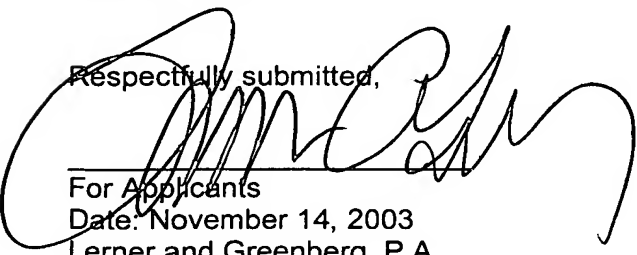
U.S. Patent No. 6,068,954 (David), dated May 30, 2000;

U.S. Patent No. 6,043,134 (Bishop), dated March 28, 2000 and

U.S. Patent No. 5,621,813 (Brown et al.), dated April 15, 1997.

If no translation of pertinent portions of any foreign language patents or publications mentioned above is included with the aforementioned copies of those applications, patents and/or publications, it is because no existing translation is readily available to the applicant. As per the Notice in 1273 OG 55 (August 5, 2003) no copies of any above-mentioned U.S. patents and U.S. patent application publications are submitted for any application filed after June 30, 2003.

Respectfully submitted,


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/kf

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: P2001,0337 Appl. No.: _____ Applicant: ROLF HEINE ET AL. Filing Date: November 14, 2003 Group Art Unit: _____			
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EXAMINER INITIALS	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	6,068,954	05/00	David		
	B	6,043,134	03/00	Bishop		
	C	5,621,813	04/97	Brown et al.		
	D					
	E					
	F					
	G					
	H					
	I					

FOREIGN PATENT DOCUMENT							
DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES NO		
	J						
	K						
	L						
	M						
	N						

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)		

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	